PATENT NUMBER

U.S. **UTILITY** Patent Application

O.I.P.E.	PATENT DATE
FA SCANNED *NOG* Q.A. *LR*	

APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/840558	D	250	310	2881	GURZO

APPLICANTS
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TITLE
Collection of secondary electrons through the objective lens of a scanning electron microscope

PTO-2040
12/99

ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)					
CLASS	**SUBCLASS**	**CLASS**	**SUBCLASS (ONE SUBCLASS PER BLOCK)**				

INTERNATIONAL CLASSIFICATION

☐ Continued on Issue Slip Inside File Jacket

☐ **TERMINAL DISCLAIMER**	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.

☐ The term of this patent subsequent to _____ (date) has been disclaimed.	(Assistant Examiner) (Date)	NOTICE OF ALLOWANCE MAILED
☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____		**ISSUE FEE**
	(Primary Examiner) (Date)	Amount Due / Date Paid
☐ The terminal ____months of this patent have been disclaimed.	(Legal Instruments Examiner) (Date)	ISSUE BATCH NUMBER

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